

Notice of Allowability	Application No.	Applicant(s)	
	09/466,925	KOKUBO, KENICHI	
	Examiner	Art Unit	
	LEYNNA T. HA	2135	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to January 6, 2005.
2. ☒ The allowed claim(s) is/are 1,2,5,6,10,12-15, and 20.
3. ☐ The drawings filed on _ are accepted by the Examiner.
4. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) ☒ All b) ☐ Some* c) ☐ None of the:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
 6. ☒ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
 - (a) ☒ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
 - 1) ☐ hereto or 2) ☒ to Paper No./Mail Date 10/1/2003.
 - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).**
7. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

- | | |
|---|---|
| <ol style="list-style-type: none"> 1. <input type="checkbox"/> Notice of References Cited (PTO-892) 2. <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) 3. <input type="checkbox"/> Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____ 4. <input type="checkbox"/> Examiner's Comment Regarding Requirement for Deposit
of Biological Material | <ol style="list-style-type: none"> 5. <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) 6. <input checked="" type="checkbox"/> Interview Summary (PTO-413),
Paper No./Mail Date <u>5/9/2005</u>. 7. <input checked="" type="checkbox"/> Examiner's Amendment/Comment 8. <input type="checkbox"/> Examiner's Statement of Reasons for Allowance 9. <input type="checkbox"/> Other _____. |
|---|---|

DETAILED ACTION

1. The pending claims are 1-26.

EXAMINER'S AMENDMENT

2. **An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.**

Authorization for this examiner's amendment was given in a telephone interview with Mr. James Howard on May 11, 2005.

The application has been amended as follows:

Please cancel claims 3-4, 7-9, 11, 16-19, and 21-26.

Replace claim 1:

A data storage device comprising:

storage means, installed in a housing, for storing predetermined confidential data;

data generation means comprising two electrodes disposed on said housing for generating data representing deflection of said housing in which said storage means is installed;

detection means for detecting physical impact applied to said housing in accordance with the data generated by said data generation means;

measure means for a measuring temperature in said housing in which said storage means is installed; and

correction means for correcting the data generated by said data generation means in accordance with the temperature measured by said measure means,

wherein said detection means detects the physical impact applied to said housing in accordance with the data representing the deflection after the correction by said correction means.

Replace claim 2:

A data storage device comprising:

storage means, installed in a housing, for storing predetermined confidential data;

data generation means comprising two electrodes disposed on said housing for generating data representing deflection of said housing in which said storage means is installed;

detection means for detecting physical impact applied to said housing by specifying the deflection of said housing in accordance with the data generated by said data generation means;

data cancel means for canceling the confidential data stored in said storage means when said detection means detects physical impact applied to said housing;

wherein said data representing deflection of said housing represents a change of capacitance between two electrodes that are disposed on said housing;

measure means for measuring a temperature in said housing in which said storage means is installed; and

correction means for correcting the data generated by said data generation means in accordance with the temperature measured by said measure means,

wherein said detection means detects the physical impact applied to said housing in accordance with the data representing the deflection after the correction by said correction means.

Replace claim 5:

A data storage device comprising:

a memory, installed in a housing having predetermined shape, for storing predetermined confidential data;

a plurality of electrodes disposed on, arranged in said housing in which said memory is installed, for generating predetermined capacitance; and

a detection processor for detecting physical impact applied to said housing in accordance with a shift of degrees of the capacitance between said electrodes;

a thermo-sensor which measure a temperature in said housing in which said memory is installed; and

a correction processor which corrects the shift of degrees of the capacitance between said electrodes in accordance with the temperature measured by said thermo-sensor,

wherein said detection processor detects the physical impact applied to said housing in accordance with the deflection of said housing after the correction by said correction processor.

Replace claim 6:

A data storage device comprising:

a memory, installed in a housing having predetermined shape, for storing predetermined confidential data;

a plurality of electrodes disposed on said housing in which said memory is installed, for generating a predetermined capacitance;

a detection processor which specifies deflection of said housing in accordance with a shift of degrees of the capacitance between said electrodes to detect physical impact applied to said housing; and

a data canceller which cancels the confidential data stored in said memory when said detection processor detects the physical impact applied to said housing;

a thermo-sensor which measure temperature in said housing in which said memory is installed; and

a correction processor which corrects the shift of degrees of the capacitance between said electrodes in accordance with the temperature measured by said thermo-sensor,

wherein said detection processor detects the physical impact applied to said housing in accordance with the deflection of said housing after the correction by said correction processor;

generating data representing deflection of a housing in which a storage device for storing predetermined confidential data is installed; and

detecting physical impact applied to said housing in accordance with the data generated by said generating data.

wherein said data representing deflection of said housing represents a change of capacitance between two electrodes that are disposed on said housing.

Replace claim 13:

A data storage device comprising:

a data storage in a housing;

a plurality of electrodes disposed on said housing;

a processor that determines a deflection of said housing based upon a capacitance between the plurality of electrodes;

wherein the data storage stores confidential data; and

wherein said processor controls said data storage to erase said confidential data when the determined deflection exceeds a predetermined range.

Allowable Subject Matter

3. Claims 1-2, 5-6, 10, 12-15 and 20 are allowed over the prior art of record.

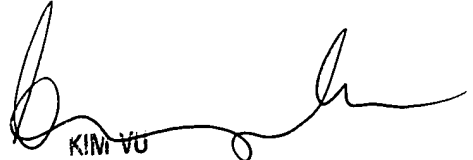
Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to LEYNNA T. HA whose telephone number is (571) 272-3851. The examiner can normally be reached on Monday - Thursday (7:00 - 5:00PM).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kim Vu can be reached on (571) 272-3859. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

LHa


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